

Status of NEPP Model-Based Mission Assurance Efforts



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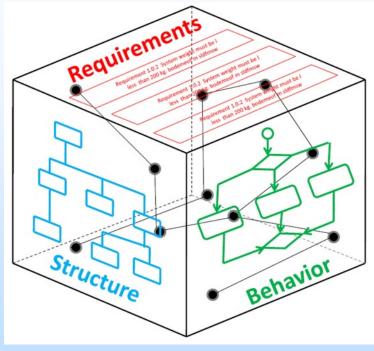
What is a Model?



 The Department of Defense defines a model as "A physical, mathematical, or otherwise logical representation of a system, entity, phenomenon, or process".

Modeling and Simulation Coordination Office, Ed., Modeling and Simulation (M&S) Glossary. 1901 N. Beauregard St., Suite 500 Alexandria, VA 22311: Department of Defense, Oct. 2011. https://www.msco.mil/MSReferences/Glossary/TermsDefinitionsI-M.aspx

- We are used to working with <u>mathematical</u> representations of systems, entities, phenomenon, or processes
- Model-Based Mission Assurance (MBMA) is adding <u>logical</u> representations of our systems and processes to enhance and improve Radiation Hardness Assurance (RHA)



M. Bajaj, B. Cole, and D. Zwemer, "Architecture to geometry - integrating system models with mechanical design," in *Proc. AIAA SPACE*, 2016.

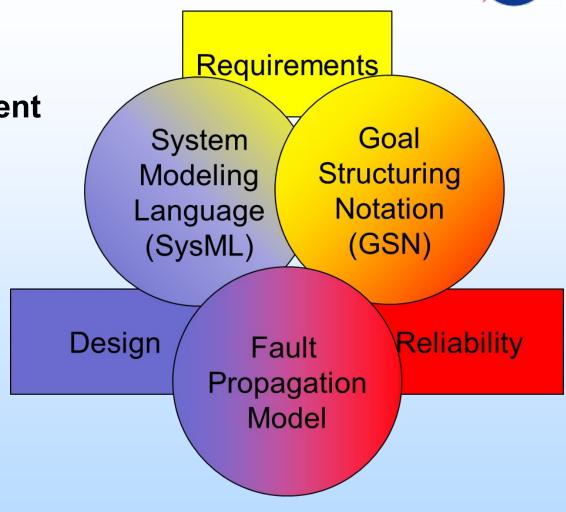
When Logical Models can improve RHA



Non-destructive Single-Event
 Effects (SEE) identified in Single-Event
 Criticality Analysis (SEECA)

OR

- Limited resources
 - Example 1: Incomplete test data for COTS system, including box-level proton testing
 - Example 2: Non-destructive SEE data taken during destructive SEE testing
 - Example 3: System is still in development and/or too complicated for simulation like FPGAs



SEAM Update Highlights



- User Guide Draft complete
 - Reviewing currently
- Part Template Library complete
 - Default library on modelbasedassurance.org
- R-GENTIC Import to SEAM
 - Working on GSN Assurance argument templates
- NASA SEAM Deployed
 - Working out a couple of usability issues
 - OSTEM Summer intern Jasleen Batra, University of Colorado

- PartsTemplate
 - **M** Annotation
 - Karaman Line Strain Strain
 - Digital
 - Discrete Power
 - Discrete RF
 - Discrete Signal
 - Embedded
 - Imager
 - Linear
 - Memory
 - Mixed Signal

 - Power Hybrid
 - Sensor

- 🌠 PartsTemplate
- Annotation
- Clocks/Timing

 - Delay-Locked Loop
 - Phase-Locked Loop
- Digital
 - Marator
 - Discrete Flip-Flops
 - Discrete Logic Gates
 - Driver (Buffer)
 - Multiplexer/Demultiplexer
 - Receiver
- Discrete Power
 - ▶ I BJT
 - ▶ I HEMT
 - ▶ IGBT
 - ▶ I JFET
 - ▶ MOSFET
 - ▶ IN Diode
 - Schottky Diode
- Discrete RF
 - Amplifier
 - Attenuator
 - Demodulator
 - Detector
 - Mixer
 - Modulator
 - Receiver

SEAM Update Highlights

- Transmitter
- Discrete Signal
 - ▶ I BJT
 - Diode
 - JFET
 - MOSFET
- Embedded
 - Digital Signal Processor
 - FPGA (Anti-fuse)
 - FPGA (Flash)
 - FPGA (SRAM)
 - Microcontroller
 - Microprocessor
- Imager
 - Marge Coupled Device
 - Mager Imager

- Focal Plane Array Assembly
- Linear
 - Marator
 - ▶ IDO
 - Dp-amp
 - Voltage Reference
 - Voltage Regulator
- Memory
 - Z Content Addressable Memory (CAM)
 - ▶ I DRAM
 - Mal-Port Memory (SRAM)
 - ▶ I EEPROM
 - FRAM
 - ▶ I MRAM
 - MAND Flash
 - MOR Flash

Power Hybrid

▶ I SDRAM

▶ I SRAM

Mixed Signal

▶ MADC

▶ I DAC

- Battery Charger
- DC-DC Converter
- Load Switch
- Motor Drives
- Multi-(Voltage) Regulator IC
- Peak Power Tracker
- Switching Power Supply

Multiplexer/Switch

Integrated PWM DC-DC Converter

Voltage-Mode PWM

Opto-Electronics

Discrete LED

Marcoupler

Photodiode

- Sensor
 - Accelerometer
 - Current Sensor
 - Hall Effect Sensor
 - Pressure Sensor
 - Readout IC
 - Resolver to Digital Con
 - Temperature Sensor

Deployed Versions of SEAM

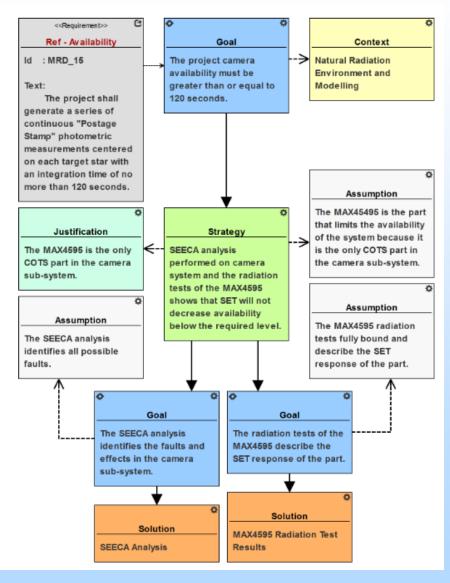


- Vanderbilt internal site
- Public site: modelbasedassurance.org (AWS)
- NASA internal site (AWS GovCloud)
- Los Alamos National Lab internal site
- AlphaCore, Inc. internal site (STTR Tech transfer)

Examples Models in SEAM



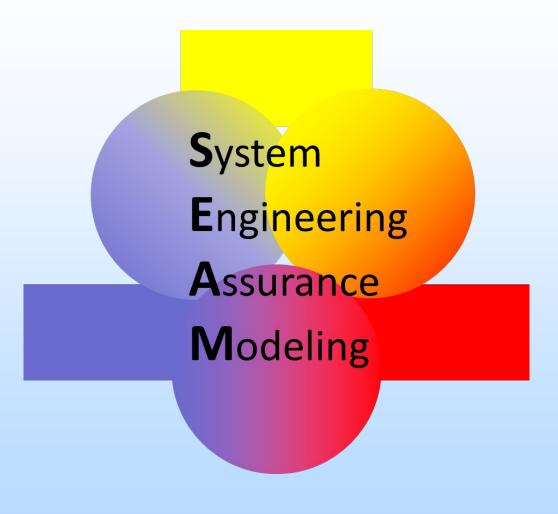
- Do not use new part template library
 - CubeSat Radiation Experiment (SEAM Model)
 - MBMA over the mission life cycle (MRQW Presentation)
 - SEECA SET Op-Amp (TNS Paper)
- Will use new part template library
 - LiDAR System next presentation
 - SpaceCube Processor Card Summer Intern project
 - Your examples!



Summary



- Reducing the barriers to entry
 - Tutorial
 - Examples
 - Part Template Library
- Increasing User Base
 - NASA and external instances
- Increasing Use Cases



Acronyms



- ADC: Analog to Digital Converter
- AWS: Amazon Web Services
- BJT: Bipolar Junction Transistor
- CAM: Content Addressable Memory
- CMOS: Complementary metal-oxide semiconductor
- COTS: Commercial Off The Shelf
- DAC: Digital to Analog Converter
- DC: Direct Current
- DT: Digital Transformation
- EEPROM: Electrically Erasable Programmable Read-Only Memory
- FPGA: Field Programable Gate Array
- FRAM: Ferroelectric Random Access Memory
- GPU: Graphical Processing Unit
- GSN: Goal Structuring Notation
- HEMT: High-Electron-Mobility Transistor
- IC: Integrated Circuit
- IGBT: Insulated-Gate Bipolar Transistor
- JFET: Junction-Gate Field-Effect Transistor
- LDO: Low-DropOut
- LED: Light Emitting Diode
- MBMA: Model-Based Mission Assurance
- MBSE: Model-Based System Engineering

- MOSFET: Metal-on-Silicon Field Effect Transistor
- MRAM: Magnetic Random Access Memory
- NAND: NOT AND
- NEPP: NASA Electronics and Packaging Program
- NOR: NOT OR
- OSMA: Office of Safety and Mission Assurance
- OSTEM: Office of STEM Engagement
- PWM: Pulse Width Modulation
- R&M: Reliability & Maintainability
- RF: Radio Frequency
- R-GENTIC: Radiation Guidelines for Notional Threat Identification and Classification
- RHA: Radiation Hardness Assurance
- SDRAM: Synchronous Dynamic Random Access Memory
- SEAM: System Engineering and Assurance Modeling
- SEE: Single Event Effects
- SEECA: Single Event Effects Criticality Assessment
- SoC: System-on-Chip
- SRAM: Static Random Access Memory
- STEM: Science, Technology, Engineering, and Mathematics
- STTR: Small Business Technology Transfer